



SEMI®
International
Standards

**NA Traceability Standards Committee
Spring Meetings, San Jose, CA
Thursday, April 1, 2010, 3:00 – 5:00 pm PDT**

AGENDA

1.0 Call to Order

- 1.1 Introduction
- 1.2 Anti-Trust Reminder
- 1.3 Intellectual Property Reminder
- 1.4 International Meeting Guidelines
- 1.5 Agenda Review

2.0 Review and Approval of Fall 2009 & February 2010 Meeting Minutes

3.0 Staff & Liaison Reports

- 3.1 SEMI Staff Report
- 3.2 Japan Liaison Report

4.0 Subcommittee & Task Force Reports

- 4.1 International Anti-Counterfeiting Task Force
- 4.2 WW Security Meeting
- 4.3 NASPO Liaison
- 4.4 ESIA Liaison

5.0 Ballot Review

- 5.1 4488, New Standard: Authentication Service Communication for Preventing / Detecting Semiconductor Counterfeit Products

6.0 Old Business

7.0 New Business

- 7.1 Update Information for SASB,ASB,CSB Document from Japan Team
- 7.2 SEMICON West Traceability Meeting Date and Time Schedule in July
- 7.3 ISO TC247 Workshop Date and Time Schedule in July
- 7.4 SEMICON Japan Workshop Concern from Japan Team in December
- 7.5 Japan ISO TC247 Workshop Concern from Japan Team in October
- 7.6 T20 IP Patent for TUV Issue
- 7.7 New Ballot Submission Summary
- 7.8 5-year Review
- 7.9 Action Item Review

8.0 Next meetings

- N. A. July 15, 2010
- Japan December 1-3, 2010

9.0 Adjourn